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Magneto-transport Study on the nanometer-scaled wires made of $Al_xGa_{1-x}N/GaN$ heterostructures WEN-YUAN PANG, IKAI LO, YU-CHI HSU, YEN-LIANG CHEN, MING-HONG GAU, W.S. LIN, C.H. CHEN, J.C. CHI-ANG, Department of physics, National Sun Yat-sen University, Kaohsiung, Taiwan, Republic of China, JEN-KAI TSAI, Center for General Education, National Formosa University, Yunlin, Taiwan, Republic of China — The electronic characteristics of nano-wires made of high-mobility $Al_xGa_{1-x}N/GaN$ heterostructures have been studied. The $Al_xGa_{1-x}N/GaN$ samples were grown on GaN-template buffer layer by plasma-assisted molecular beam epitaxy. We obtained the mobility and carrier density of two-dimensional electron gas to be 9328 cm²/Vs and 7.917x10¹² cm⁻² by conventional van der pauw Hall measurement at temperature of 77K, respectively. We prepared the samples of field-effect-transistors and reduced the width of the conducting channel from $1\mu m$ to 100 nm by Focus Ion Beam. The Shubnikovde Haas oscillations were observed by magneto-resistance measurement at 0.3 K and the electronic properties for the samples of different channel widths were under investigation.

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